

Accelerated Life Test Data

UTMC PROM FIT Rate Summary (W/ PPC)

Test Units (w/ PPC II)	Lot Number	Units	Life Test Hours at 150C	Cummulative Life Test Hours at 150C	Device Hours (55C equivalent)	64K PROM Device Hours (Equivalent)	Bit Failures	Comments
64K PROM (WO7430)	QS52561	114	500.9	500	11968.74	1.36E+06	0	
64K PROM (WO7430)	QS52561	114	562.2	1063.1	13433.47	1.53E+06	0	
64K PROM (WO7430)	QS52561	136	504.1	1567.2	12045.20	1.64E+06	0	
64K PROM (WO7430)	QS52561	136	516.7	2083.9	12346.27	1.68E+06	0	
64K PROM (WO7430)	QS52561	136	1024.4	3108.3	24477.49	3.33E+06	1	*bin 14, noisy outputs, unrelated to antifuse
256K PROM (0NYD)	AS20605 AS20606 AS22622	161	258.1	258.1	6167.16	3.97E+06	0	
256K PROM (0NYD)	AS20605 AS20606 AS22622	161	279.8	537.9	6685.67	4.31E+06	0	
256K PROM (0NYD)	AS20605 AS20606 AS22622	138	518.1	1056	12379.72	6.83E+06	1	*bin12, antifuse failure
256K PROM (0NYD)	AS20605 AS20606 AS22622	160	690.9	1746.9	16508.68	1.06E+07	0	
256K PROM (0NYD)	AS20605 AS20606 AS22622	160	211.8	1958.7	5060.85	3.24E+06	0	
64K PROM (0NVXCGPC)	AS13627	23	500.2	500.2	11952.01	2.75E+05	0	
64K PROM (0NHK)	AS13627	22	584.3	584.3	13961.54	3.07E+05	0	
256K PROM (0NVPRS)	AS19696 AS22633	24	501.8	501.8	11990.24	1.15E+06	0	
256K PROM (0NYD)	AS20605 AS20606 AS22622	166	3371.8	6916.8	80567.35	5.35E+07	0	
64K PROM (WO7430)	QS52561	135	2636.4	5744.7	62995.36	8.50E+06	0	
256K PROM (0NYD)	AS20605 AS20606 AS22622	166	5173.7	12090.5	123622.79	8.21E+07	0	
256K PROM	W07618	90	1082.2	1082.2	25858.59	9.31E+06	1	
256K PROM	W07618	89	3075.8	4158	73494.59	2.62E+07	0	
Total					525515.72	2.20E+08	3	

64K PROM FIT Rate Summary (W/ PPC II)

MTTF	8,356 years	FIT (MLE)	14
MTTF	6,004 years	FIT 60% UCL	19
60% LCL			
Reliability Over	15 Years	MLE	99.82%
Reliability Over	15 Years	60% LCL	99.75%

256K PROM FIT Rate Summary (W/ PPC II)

MTTF	2,089 years	FIT (MLE)	55
MTTF	1,501 years	FIT 60% UCL	76
60% LCL			
Reliability Over	15 Years	MLE	99.28%
Reliability Over	15 Years	60% LCL	99.01%